
Lecture 7

PN Junctions

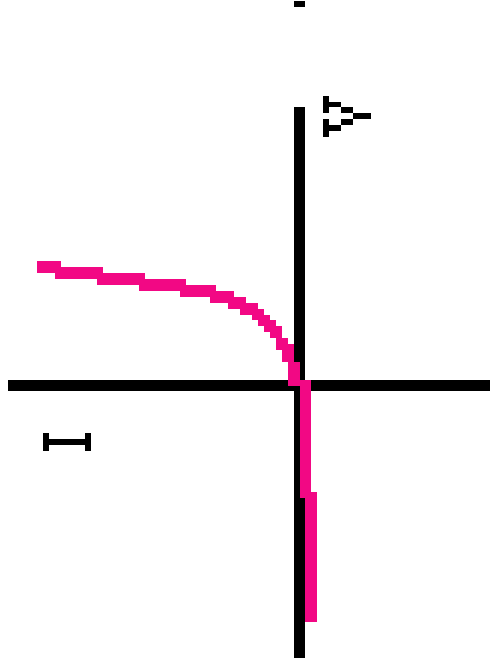
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Active Circuit Elements

- Why are they desirable?
 - Much greater flexibility in circuit applications.
 - What's possible/impossible? Can you make it from a single device, or do you need to combine several into one unit? If you could have a device that does anything, what would it be?
- How are they made?
 - Exploit physical properties of the natural world
 - Enhance/alter what's available naturally

Reading: Sedra & Smith 3.3, Streetman Ch 5

PN Junction Diode

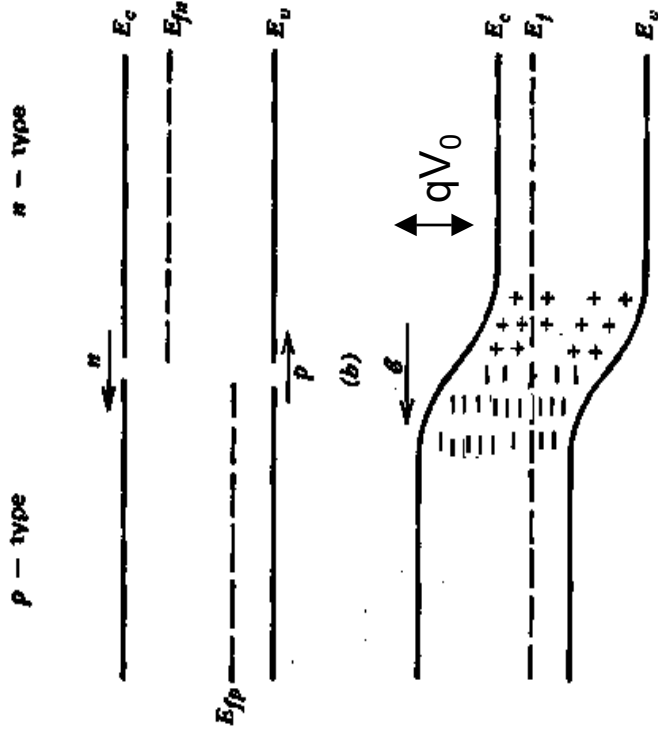


$$I = I_0 \left(e^{qV/kT} - 1 \right)$$

Subtracting I_0 becomes negligible
for higher applied V . $I \gg I_0$

$$\frac{kT}{q} \approx 26mV \text{ at room temp}$$

Band Diagram



- P-type material is brought into contact with n-type material. The Fermi levels *must* be at equilibrium.
- Band Bending: The conduction and valence bands “bend” to bring the Fermi levels into contact.

What happens when p-type meets n-type?

- Holes diffuse from the p-type into the n-type, electrons diffuse from the n-type into the p-type, creating a **diffusion current**. The diffusion equation is given by

$$J_n = qD_n \frac{dn}{dx} \quad D_n = \text{diffusion constant}$$

- Once the holes [electrons] cross into the n-type [p-type] region, they **recombine** with the electrons [holes].
- This recombination “strips” the n-type [p-type] of its electrons near the boundary, creating an electric field due to excess charge.
- The region “stripped” of carriers is called the space-charge region, or depletion region.
- V_0 is the contact potential that exists due to the electric field. $E(x) = -\frac{dV}{dx}$
- Some carriers are **generated** and make their way into the depletion region where they are whisked away by the electric field, creating a **drift current**.

Equilibrium motion of carriers

$$J_n(x) = q\mu_n n(x)E(x) + qD_n \frac{dn(x)}{dx}$$

The **diffusion current** is determined by the number of carriers able to overcome the **potential**.

$$J_p(x) = q\mu_p p(x)E(x) + qD_p \frac{dp(x)}{dx}$$

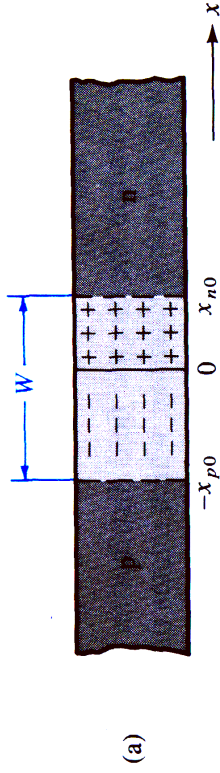
Drift *Diffusion*

The **drift current** is determined by the generation of minority carriers which then feel the field and get whisked across.

This generation rate is determined by the **temperature**.

At equilibrium, the two components are equal $\Rightarrow \frac{D}{\mu} = \frac{kT}{q}$ *Einstein's relation*

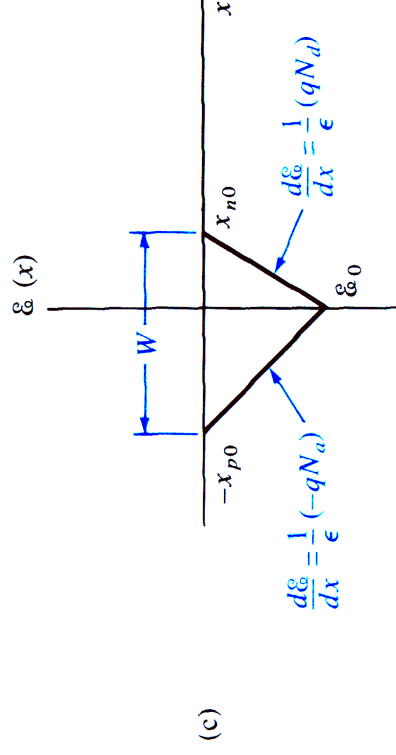
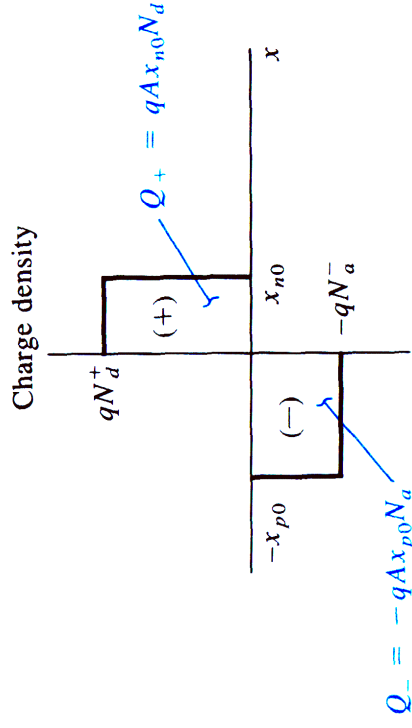
Space Charge at a junction



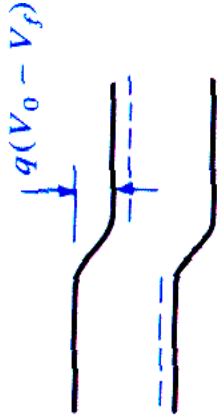
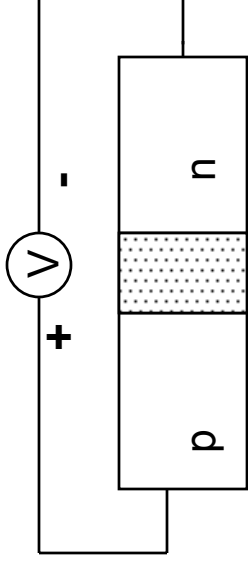
$$qx_{p0}AN_a = qx_{n0}AN_d$$

$$\frac{x_{n0}}{x_{p0}} = \frac{N_a}{N_d}$$

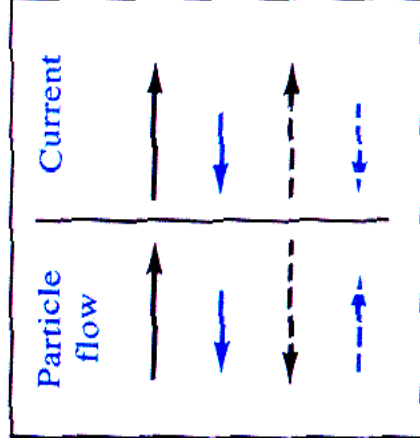
$$W_{dep} = \sqrt{\frac{2\epsilon}{q} \left(\frac{1}{N_a} + \frac{1}{N_d} \right) V_0}$$



Forward Bias

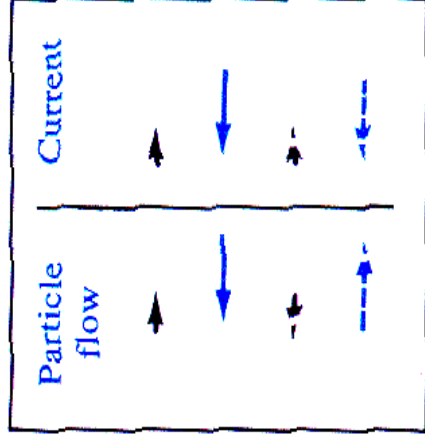
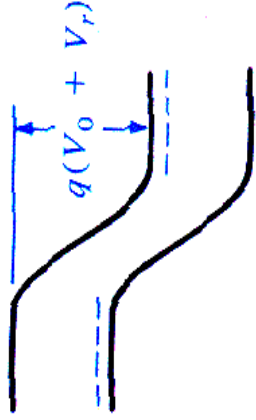
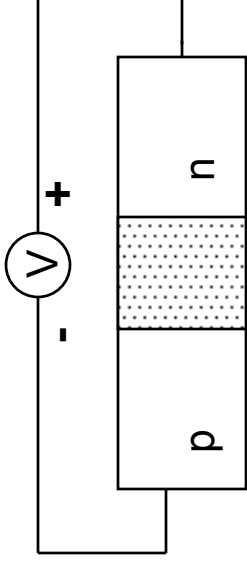


- Forward bias: apply a positive voltage to the p-type, negative to n-type.
- Decrease the built-in potential, lower the barrier height.
- Increase the number of carriers able to diffuse across the barrier
- Diffusion current increases
- Drift current remains the same
- Current flows from p to n



- (1) Hole diffusion (3) Electron diffusion
 (2) Hole drift (4) Electron drift

Reverse Bias

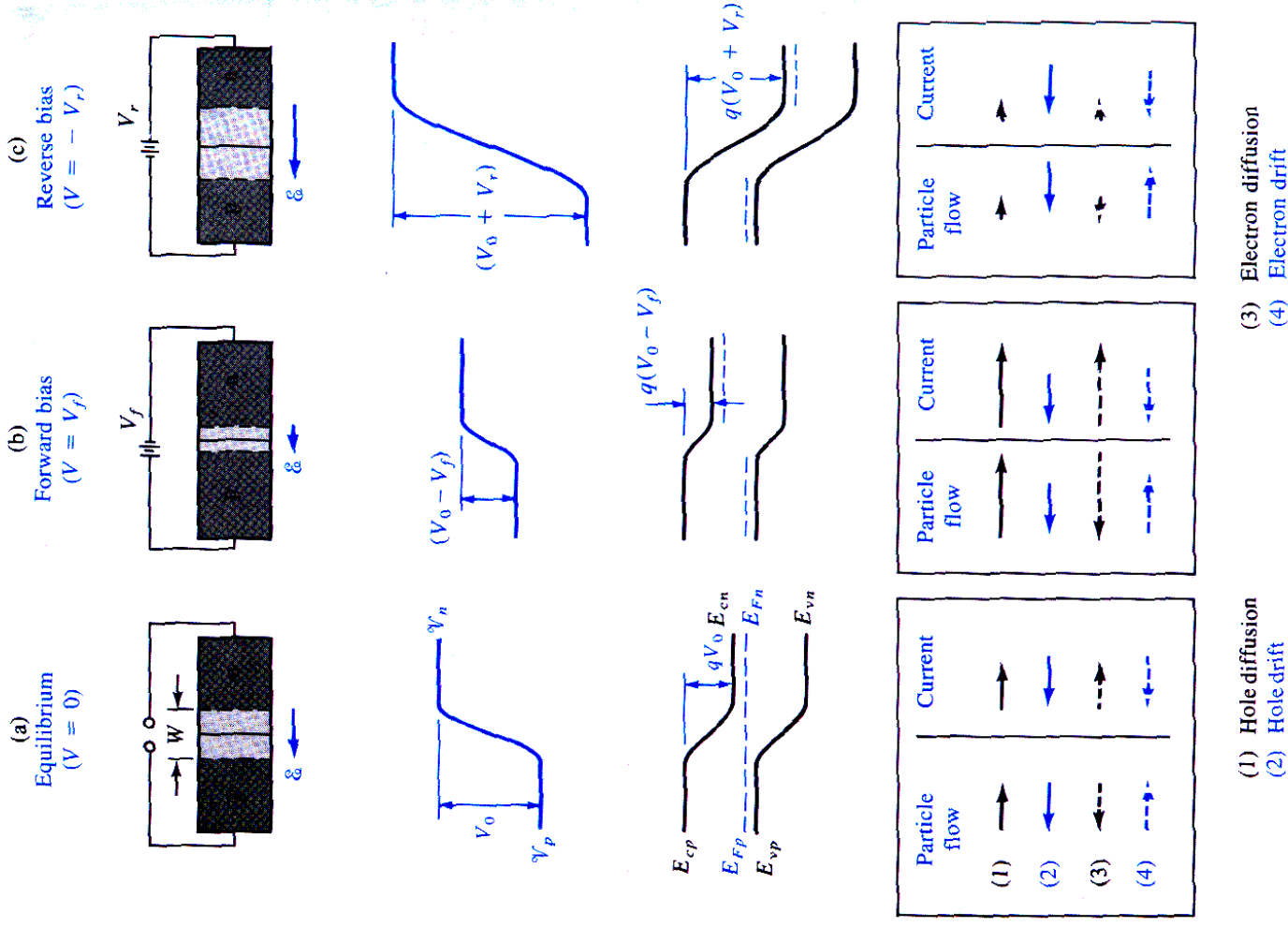


- (1) Hole diffusion
- (2) Hole drift
- (3) Electron diffusion
- (4) Electron drift

- Reverse bias: apply a negative voltage to the p-type, positive to n-type.
- Increase the built-in potential, lower the barrier height.
- Decrease the number of carriers able to diffuse across the barrier.
- Diffusion current decreases.
- Drift current remains the same.
- Almost no current flows. Reverse leakage current, I_0 , is the drift current, flowing from n to p.

Review of Biasing

- Applying a bias adds or subtracts to the built-in potential.
- This changes the diffusion current, making it harder or easier for the carriers to diffuse across.
- The drift current is essentially constant, as it is dependent on temperature.



Quantitative Analysis of Current Flow

Consider the holes that can now diffuse across to the n-type region.

$$p_n(x_n) = p_{n0} e^{qV/kT}$$

$$p_n(x) = \left[p_{n0} + (p_n(x_n) - p_{n0}) e^{-\frac{(x-x_n)}{L_p}} \right]$$

$$J_p = q \frac{D_p}{L_p} p_{n0} \left(e^{qV/kT} - 1 \right) e^{-(x-x_n)/L_p}$$

L_p = *diffusion length*

But with the applied voltage, the electrons that get consumed by the holes are replenished from the circuit, at a constant rate determined by the value at x_n , simplifying this to...

Analysis Continued

$$J_p = q \frac{D_p}{L_p} p_{n0} \left(e^{qV/kT} - 1 \right)$$

Similarly, for the electrons in the p-type, one obtains

$$J_n = q \frac{D_n}{L_n} n_{p0} \left(e^{qV/kT} - 1 \right)$$

A bit of manipulation gives us

$$I = Aqn_i^2 \left(\frac{D_p}{L_p N_d} + \frac{D_n}{L_n N_a} \right) \left(e^{qV/kT} - 1 \right)$$

$$I_0 = Aqn_i^2 \left(\frac{D_p}{L_p N_d} + \frac{D_n}{L_n N_a} \right)$$

- Reverse saturation current, the drift current, depends directly on the area of the junction.
- Also depends on n_i , which is dependent on temperature.

Capacitance

The junction acts as a parallel plate capacitor. Charge builds up on both sides.

$$C_j = \frac{\varepsilon_s A}{W_{dep}} \quad W_{dep} = \sqrt{\left(\frac{2\varepsilon_s}{q}\right)\left(\frac{1}{N_a} + \frac{1}{N_d}\right)(V + V_0)}$$

This expression is accurate for reverse bias, but not very good for forward bias. $V + V_0$ is the total voltage across the junction under reverse bias conditions.

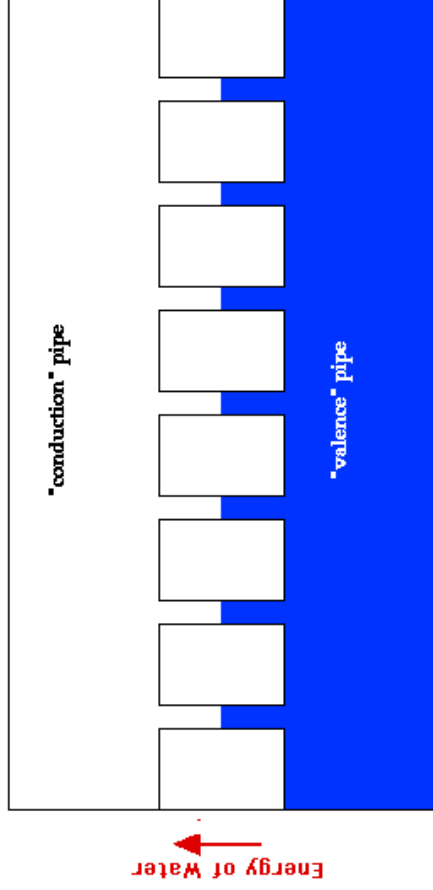
We can also write this as

$$C_j = \frac{C_{j0}}{\left(1 + \frac{V_R}{V_0}\right)}$$

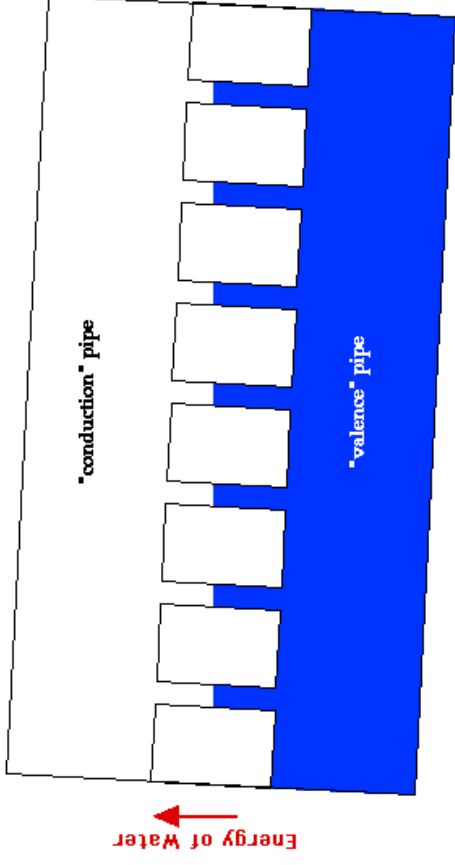
Notice we can use a diode as a varactor! (Voltage controlled capacitor.)

Two pipe/fluid model

Insulator at equilibrium - i.e. there is no applied external potential

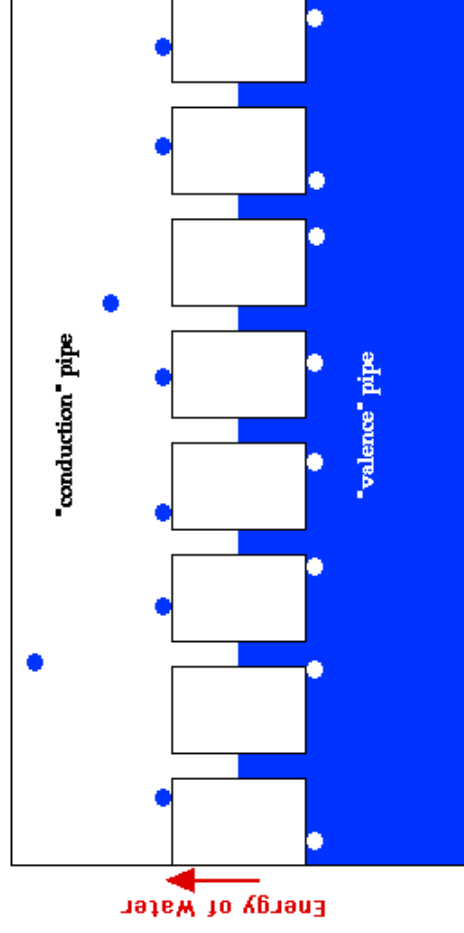


Insulator with an applied external potential - no current flow possible

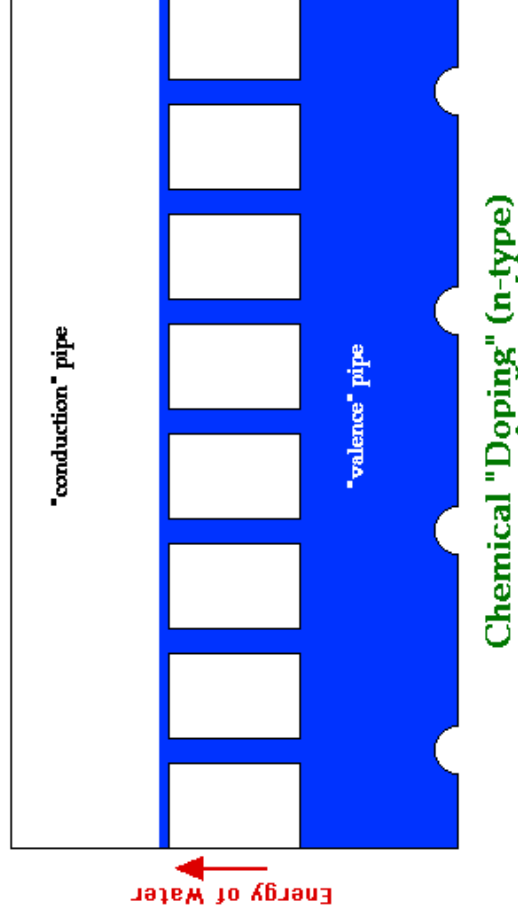


More fluid Models

Intrinsic semiconductor at equilibrium

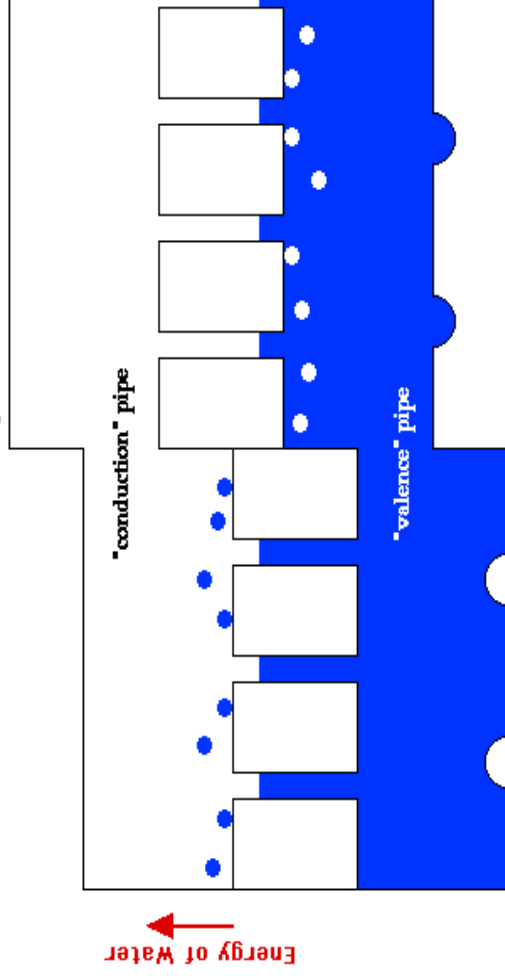


Semiconductor doped with a "donor" impurity

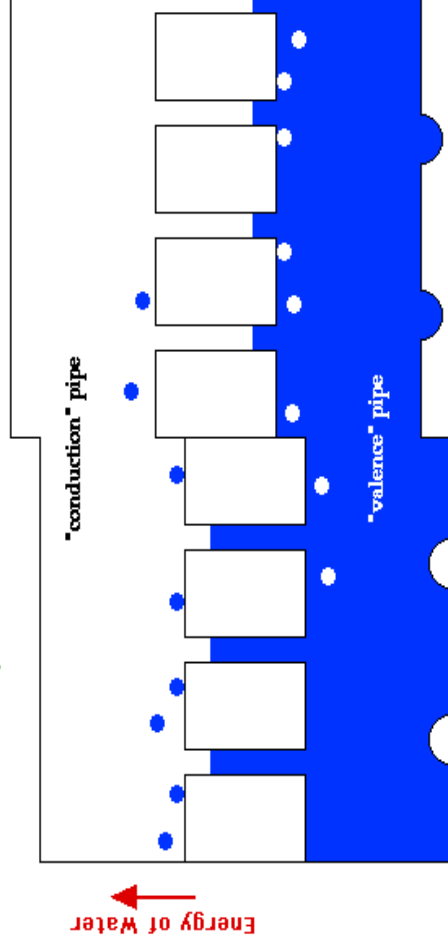


And more!

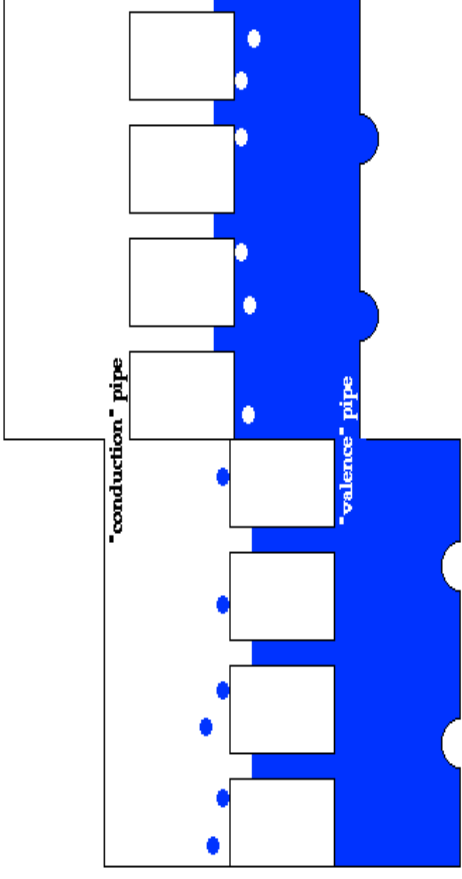
Junction at Equilibrium



Junction with a *Forward* Bias

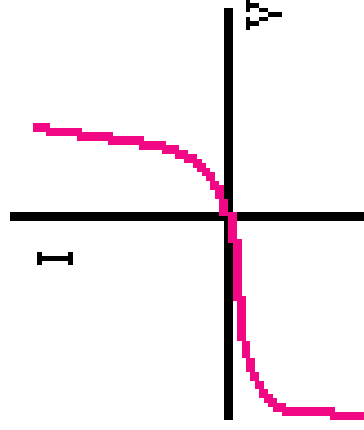


Junction with a *Reverse* Bias



Reverse Breakdown

- Zener Breakdown: The bands bend so much that carriers tunnel through the depletion region. This will occur in heavily doped junctions when the n-side conduction band appears opposite the p-side valence band.
- Avalanche Breakdown: carriers have enough energy to ionize an electron-hole-pair, creating more highly energetic carriers, which collide to form more EHPs, which creates...

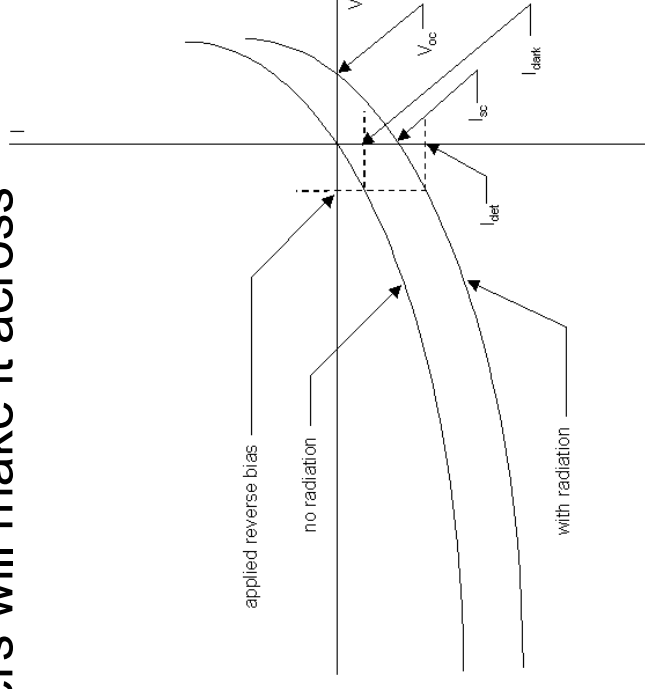


Photodiodes

- Diodes have an optical generation rate. Carriers are created by shining light with intensity greater than the bandgap.
- One wants large depletion widths and long diffusion lengths, as it is only in these areas that excited carriers will make it across the junction.
- Photodetector: operate in third quadrant.

Compromise between speed and junction width leads to a p-intrinsic-n junction, where carriers will be rapidly swept across, and can quickly diffuse in the p and n regions.

- Solar Cell: operating in the fourth quadrant generates current, though small.



Light Emitting Diodes

- When electrons and holes combine, they release energy.
- This energy is often released as heat into the lattice, but in some materials, known as direct bandgap materials, they release light.
- Engineering LEDs can be difficult, but has been done over a wide range of wavelengths.
- This illustration describes the importance of the plastic bubble in directing the light so that it is more effectively seen.

